Statistical Model Checking and Rare Events

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Probabilistic Verification

- Verification of stochastic system models via statistical model checking
- Temporal logic specification:
 - "the amount of p53 exceeds 10⁵ within 20 minutes"
- If Φ = "p53 exceeds 10⁵ within 20 minutes"

Probability $(\Phi) = ?$

Equivalently

- A biased coin (Bernoulli random variable):
 - Prob (Heads) = p
 Prob (Tails) = 1-p
 - p is unknown

- Question: What is p?
- A solution: flip the coin a number of times, collect the outcomes, and use statistical estimation

Statistical Model Checking

<u>Key idea</u>

(Haakan Younes, 2001)

- System behavior w.r.t. property Φ can be modeled by a Bernoulli random variable of parameter p:
 - System satisfies \$\varPhi\$ with (unknown) probability \$p\$
- Question: What is p?
- Draw a sample of system simulations and use:
 - Statistical estimation: returns "p in interval (a,b)" with high probability

Statistical Model Checking

- Statistical Model Checking is a Monte Carlo method
- Problems arise when p is very small (rare event)
- The number of simulations (coin flips) needed to estimate p accurately grows too large
- Need to deal with this ...



• Estimate Prob(X \ge t) = p_t , when p_t is <u>small</u> (say 10⁻⁹)

Rare events

- Estimate Prob(X $\ge t$) = p_t , when p_t is <u>small</u> (say 10⁻⁹)
- Standard (Crude) Monte Carlo: generate K i.i.d. samples of X; return the estimator e_K

$$\boldsymbol{e}_{\boldsymbol{K}} = \frac{1}{K} \sum_{i=1}^{K} I(X_i \ge t) = \frac{k_t}{K}$$

• Prob $(e_K \rightarrow p_t) = 1$ for $K \rightarrow \infty$ (strong law LN)



- $E[e_{K}] = p_{t}$
- $Var[e_K] = \frac{p_t(1-p_t)}{K}$

Rare events

- $E[e_{\kappa}] = p_t$
- $Var[e_K] = \frac{p_t(1-p_t)}{K}$
- By the Central Limit Theorem (CLT), the distribution of e_K converges to a normal distribution with:

• mean
$$p_t$$

• variance $\frac{p_t(1-p_t)}{K}$
• Relative Error (RE) = $\frac{\sqrt{\operatorname{var}[e_K]}}{\operatorname{E}[e_K]} = \frac{\sqrt{p_t(1-p_t)}}{p_t\sqrt{K}}$



• RE =
$$\frac{\sqrt{p_t(1-p_t)}}{p_t\sqrt{K}}$$

- Fix *K*, then RE is unbounded as $p_t \rightarrow 0$
- More accuracy → more samples
- Want confidence interval of relative accuracy δ and coverage probability c, i.e., estimate e_κ must satisfy:

$$Prob(|e_{\kappa}-p_t| < \delta \cdot p_t) \ge c$$

How many samples do we need?

Rare events

 From the CLT, a 99% (approximate) confidence interval of relative accuracy δ needs about

$$K \approx \frac{1 - p_t}{p_t \delta^2}$$
 samples

Thus, Prob($|e_{\kappa} - p_t| < \delta p_t$) ≈ 0.99

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- Examples:
 - $p_t = 10^{-9}$ and $\delta = 10^{-2}$ (*ie*, 1% relative accuracy) we need about 10^{13} samples!!
 - Bayesian estimation requires about $6x10^6$ samples with $p_t=10^{-4}$ and $\delta = 10^{-1}$

A solution

- Importance Sampling (1940s)
- A variance-reduction technique
- Can result in dramatic reduction in sample size

The fundamental Importance Sampling identity

$$p_t = E[I(X \ge t)]$$

$$= \int I(x \ge t)f(x) dx$$

$$= \int I(x \ge t)\frac{f(x)}{f_*(x)}f_*(x) dx$$

$$= \int I(x \ge t)W(x)f_*(x) dx$$

$$= E_*[I(X \ge t)W(X)]$$
f is the density of *X*

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likelihood ratio
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- Estimate $p_t = E[X \ge t] = Prob(X \ge t)$
- A sample X_1, \dots, X_k iid as f
- The crude Monte Carlo estimator is

$$\hat{p_t} = \frac{1}{K} \sum_{i=1}^K I(X_i \ge t) = \frac{k_t}{K}, \qquad X_i \sim f$$

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- Define a biasing density f*
- Compute the IS estimator

$$\hat{p_t} = \frac{1}{K} \sum_{i=1}^K I(X_i \ge t) W(X_i), \qquad X_i \sim f_*$$

where
$$W(x) = \frac{f(x)}{f_*(x)}$$
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sampling from f_* !
where $W(x) = \frac{f(x)}{f_*(x)}$ is the likelihood ratio

Need to choose a "good" biasing density (low variance)

• Optimal density:
$$f_*(x) = \frac{I(x \ge t)f(x)}{p_t}$$

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Zero variance! (But ...)

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Cross-Entropy Method (R. Rubinstein)

- Suppose the density of X in a family of densities {f(· ;v)}
 - the "nominal" f is f(x;u)
- <u>Key idea</u>: choose a parameter v such that the *distance* between f_* and $f(\cdot;v)$ is minimal
- The Kullback-Leibler divergence (cross-entropy) is a measure of "distance" between two densities
- First used for rare event simulation by Rubinstein (1997)

The KL divergence (cross-entropy) of densities g, h is

$$D(g,h) = E_g \left[\ln \frac{g(X)}{h(X)} \right] = \int g(x) \ln g(x) dx - \int g(x) \ln h(x) dx$$

- $D(g,h) \ge 0$ (= 0 IFF g = h)
- $D(g,h) \neq D(h,g)$

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optimal density f_*

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- Step 2 is "easy"
- Step 1 is not so easy

- Step 1:
- *v*_{*} =

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$$V_* = \arg\min_{V} E_{f_*} \left[\ln \frac{f_*(X)}{f(X;v)} \right] = \arg\min_{V} \int f_*(x) \ln f_*(x) dx - \int f_*(x) \ln f(x;v) dx$$

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$$= \underset{v}{\arg\max} \int I(x \ge t) f(x;u) \ln f(x;v) dx = \underset{v}{\arg\max} E_u[I(X \ge t) \ln f(X;v)]$$

For certain families {f(·;v)} (eg, one-dim exponential)
 the problem

$$v_* = \arg \max_{v} E_u[I(X \ge t) \ln f(X;v)]$$
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can be solved analytically:

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• In practice: get $X_1, ..., X_k$ samples iid as $f(\cdot; u)$ and compute the approximation

$$\bar{v}_* = \frac{\sum_{i=1}^{K} [I(X_i \ge t)X_i]}{\sum_{i=1}^{K} [I(X_i \ge t)]}$$

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In general, one would have to (numerically) solve the problem

$$\frac{1}{K}\sum_{i=1}^{K}I(X_i \ge t)\nabla \ln f(X_i;v) = 0$$

• Problem: If $\{X \ge t\}$ is a rare event, then this fails

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Most terms in both sums will be zero!

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Now compute v_{*} "as usual". Iterate until t'=t

- Does NOT work with statistical model checking
- Problem: sample quantile computation
- Order the sample performances

$$S_{(1)} \leq \dots \leq S_{(i)} \leq \dots \leq S_{(K)}$$

$$(1 - \rho)K$$

 In statistical model checking, sample performances are either 0 (property false) or 1 (property true)

• However ...

$$v_* = \frac{E_u[I(X \ge t)X]}{E_u[I(X \ge t)]} = \frac{E_w[I(X \ge t)W(X;u,w)X]}{E_w[I(X \ge t)W(X;u,w)]}$$

where
$$W(x; u, w) = \frac{f(x; u)}{f(x; w)}$$
 for an arbitrary parameter w

Work in progress

Example: Fuel Control System

The Stateflow/Simulink model



Verification

- We want to estimate the probability that \mathcal{M} , FaultRate $\models F^{100} G^1$ (FuelFlowRate = 0)
- "It is the case that within 100 seconds, FuelFlowRate is zero for 1 second"
- FaultRate = 1/3600s (same value for the three sensors)

- Ran cross-entropy method to estimate optimal biasing density with *FaultRates* = {1/7, 1/8, 1/9}
- Used 100 samples for this, and obtained

NewRates_{*} = {1/2.007, 1/1.0113, 1/1.7277}

- Run importance sampling with 1,000 samples and NewRates*
 - Probability estimate 9.1855x10⁻¹⁵

Conclusions

- Need to be able to deal with rare events in statistical model checking
- The Cross-Entropy method is an interesting, semiautomatic technique
- Research: adaptive technique for stat. model checking
- [Further benefit: cross-entropy method also applies to optimization, eg, finding policies for MDPs]



Questions?